## Search Notes



10748657

Applicant(s)/Patent Under Reexamination

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Art Unit

## SEARCHED

Class	Subclass	Date	Examiner		
382	319	3/14/2009	SRK		
358	488	3/14/2009	SRK		

## SEARCH NOTES

Search Notes	Date	Examiner
NPL search IEEE explore and INSPEC for pre-scanning methods	3/14/2009	SRK
EAST text search of above-cited classes for automatic pre-scanning methods	3/14/2009	SRK

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/S. R. K./ Examiner.Art Unit 2624